

Design&Test



ALEXANDER TORRES 2016

CHALLENGES AND OPPORTUNITIES IN ANALOG/MIXED-SIGNAL CAD

- Retention Testing Methodology for STTRAM
- Efficient Global Optimization of Analog Circuits Using Predictive Response Surface Models on Discretized Design Space
 - Using Presilicon Knowledge to Excite Nonlinear Failure Modes in Large Mixed-Signal Circuits
 - Verifying Inevitability of Oscillation in Ring Oscillators Using the Deductive SOS-QE Approach
- Design of Mixed-Signal Systems With Asynchronous Control • EM-Based On-Chip Aging Sensor for Detection of Recycled ICs



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